

Features

- Temperature range:
 - Commercial: 0 °C to 70 °C
 - Automotive-A: -40 °C to 85 °C
- High speed
 - $t_{AA} = 15 \text{ ns}$
- Low active power
- Low CMOS standby power
 - 2.75 mW (max.)
- 2.0 V data retention (400 μW at 2.0 V retention)
- Automatic power-down when deselected
- TTL-compatible inputs and outputs
- Easy memory expansion with $\overline{\text{CE}}$ and $\overline{\text{OE}}$ features
- Available in Pb-free and non Pb-free 44-pin TSOP II and molded 44-pin (400-Mil) SOJ packages

Functional Description

The CY7C1041BN is a high-performance CMOS static RAM organized as 262,144 words by 16 bits.

Writing to the device is accomplished by taking Chip Enable ($\overline{\text{CE}}$) and Write Enable ($\overline{\text{WE}}$) inputs LOW. If Byte Low Enable ($\overline{\text{BLE}}$) is LOW, then data from I/O pins (I/O₀ through I/O₇), is written into the location specified on the address pins (A₀ through A₁₇). If Byte High Enable ($\overline{\text{BHE}}$) is LOW, then data from I/O pins (I/O₈ through I/O₁₅) is written into the location specified on the address pins (A₀ through A₁₇).

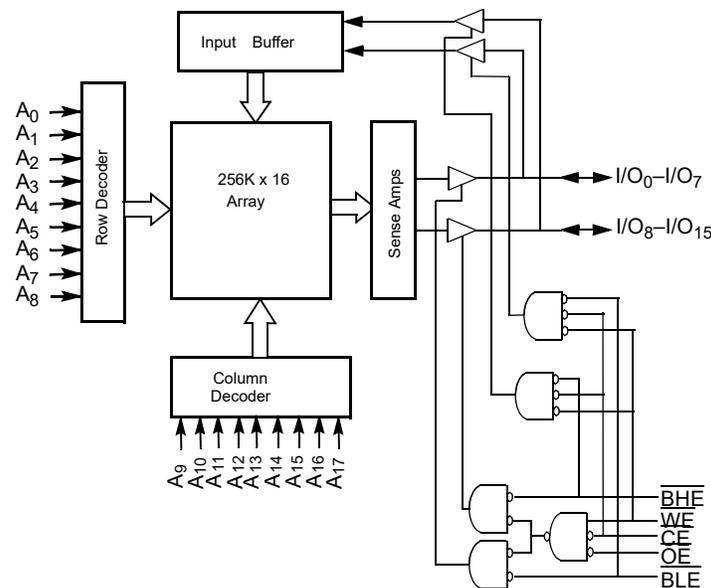
Reading from the device is accomplished by taking Chip Enable ($\overline{\text{CE}}$) and Output Enable ($\overline{\text{OE}}$) LOW while forcing the Write Enable ($\overline{\text{WE}}$) HIGH. If Byte Low Enable ($\overline{\text{BLE}}$) is LOW, then data from the memory location specified by the address pins will appear on I/O₀ to I/O₇. If Byte High Enable ($\overline{\text{BHE}}$) is LOW, then data from memory will appear on I/O₈ to I/O₁₅. See the truth table at the back of this data sheet for a complete description of read and write modes.

The input/output pins (I/O₀ through I/O₁₅) are placed in a high-impedance state when the device is deselected ($\overline{\text{CE}}$ HIGH), the outputs are disabled ($\overline{\text{OE}}$ HIGH), the $\overline{\text{BHE}}$ and $\overline{\text{BLE}}$ are disabled ($\overline{\text{BHE}}$, $\overline{\text{BLE}}$ HIGH), or during a write operation ($\overline{\text{CE}}$ LOW, and $\overline{\text{WE}}$ LOW).

The CY7C1041BN is available in a standard 44-pin 400-mil-wide body width SOJ and 44-pin TSOP II package with center power and ground (revolutionary) pinout.

For a complete list of related documentation, click [here](#).

Logic Block Diagram



Contents

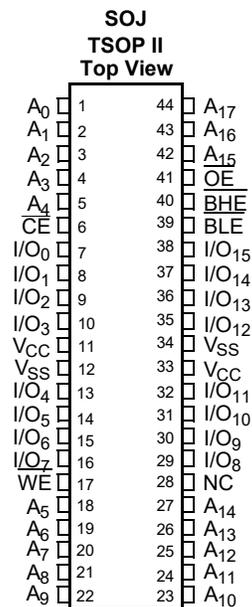
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Selection Guide

Description		-15	-20	Unit
Maximum access time		15	20	ns
Maximum operating current	Commercial	190	170	mA
	Automotive-A	–	190	–
Maximum CMOS standby current	Commercial	0.5	0.5	mA
	Automotive-A	–	6	

Pin Configurations

Figure 1. 44-pin TSOP II / SOJ pinout (Top View)



Maximum Ratings

Exceeding maximum ratings may shorten the useful life of the device. These user guidelines are not tested.

Storage temperature -65 °C to +150 °C

Ambient temperature
with power applied -55 °C to +125 °C

Supply voltage
on V_{CC} to relative GND^[1] -0.5 V to +7.0 V

DC voltage applied to outputs
in High Z State ^[1] -0.5 V to V_{CC} + 0.5 V

DC input voltage ^[1] -0.5 V to V_{CC} + 0.5 V

Current into outputs (LOW) 20 mA

Operating Range

Range	Ambient Temperature ^[2]	V _{CC}
Commercial	0 °C to +70 °C	5 V ± 0.5
Automotive-A	-40 °C to +85 °C	

Electrical Characteristics

Over the Operating Range

Parameter	Description	Test Conditions	-15		-20		Unit	
			Min	Max	Min	Max		
V _{OH}	Output HIGH voltage	Min V _{CC} , I _{OH} = -4.0 mA	2.4	-	2.4	-	V	
V _{OL}	Output LOW voltage	Min V _{CC} , I _{OL} = 8.0 mA	-	0.4	-	0.4	V	
V _{IH} ^[1]	Input HIGH voltage	-	2.2	V _{CC} + 0.5	2.2	V _{CC} + 0.5	V	
V _{IL} ^[1]	Input LOW voltage	-	-0.5	0.8	-0.5	0.8	V	
I _{IX}	Input load current	GND ≤ V _{IN} ≤ V _{CC}	-1	+1	-1	+1	µA	
I _{OZ}	Output leakage current	GND ≤ V _{OUT} ≤ V _{CC} , Output Disabled	-1	+1	-1	+1	µA	
I _{CC}	V _{CC} operating supply current	Max V _{CC} , f = f _{MAX} = 1/t _{RC}	Commercial	-	190	-	170	mA
			Automotive-A	-	-	-	190	mA
I _{SB1}	Automatic CE power-down current – TTL inputs	Max V _{CC} , $\overline{CE} \geq V_{IH}$, V _{IN} ≥ V _{IH} or V _{IN} ≤ V _{IL} , f = f _{MAX}	-	40	-	40	mA	
I _{SB2}	Automatic CE power-down current – CMOS inputs	Max V _{CC} , $\overline{CE} \geq V_{CC} - 0.3$ V, V _{IN} ≥ V _{CC} - 0.3 V, or V _{IN} ≤ 0.3 V, f = 0	Commercial	-	0.5	-	0.5	mA
			Automotive-A	-	-	-	6	mA

Notes

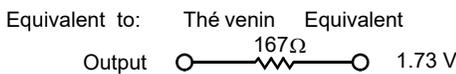
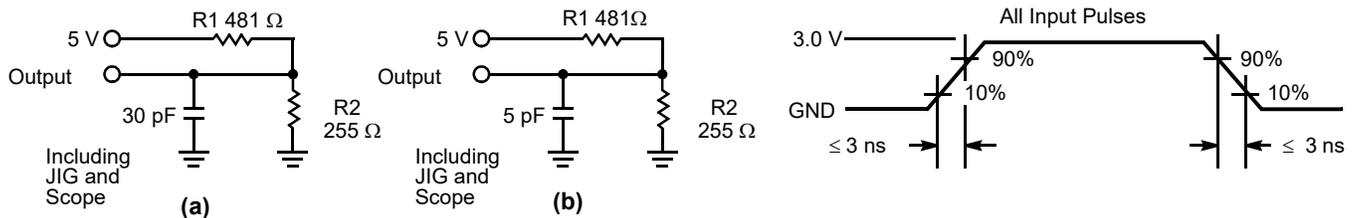
- V_{IL} (min.) = -2.0 V for pulse durations of less than 20 ns.
- T_A is the case temperature.

Capacitance

Parameter ^[3]	Description	Test Conditions	Max	Unit
C _{IN}	Input capacitance	T _A = 25 °C, f = 1 MHz, V _{CC} = 5.0 V	8	pF
C _{OUT}	I/O capacitance		8	pF

AC Test Loads and Waveforms

Figure 2. AC Test Loads and Waveforms



Data Retention Characteristics

Over the Operating Range (Commercial only)

Parameter	Description	Conditions ^[4]	Min	Max	Unit
V _{DR}	V _{CC} for data retention	–	2.0	–	V
I _{CCDR}	Data retention current	V _{CC} = V _{DR} = 2.0 V, CE ≥ V _{CC} – 0.3 V, V _{IN} ≥ V _{CC} – 0.3 V or V _{IN} ≤ 0.3 V	–	200	μA
t _{CDR} ^[5]	Chip deselect to data retention time		0	–	ns
t _R ^[6]	Operation recovery time		t _{RC}	–	ns

Data Retention Waveform

Figure 3. Data Retention Waveform



Notes

3. Tested initially and after any design or process changes that may affect these parameters.
4. No input may exceed V_{CC} + 0.5 V.
5. Tested initially and after any design or process changes that may affect these parameters.
6. t_r ≤ 3 ns for the -15 speed. t_r ≤ 5 ns for the -20 and slower speeds.

Switching Characteristics

Over the Operating Range

Parameter ^[7]	Description	-15		-20		Unit
		Min	Max	Min	Max	
Read Cycle						
t_{power}	V_{CC} (typical) to the first access ^[8]	1	–	1	–	μ s
t_{RC}	Read cycle time	15	–	20	–	ns
t_{AA}	Address to data valid	–	15	–	20	ns
t_{OHA}	Data hold from address change	3	–	3	–	ns
t_{ACE}	\overline{CE} LOW to data valid	–	15	–	20	ns
t_{DOE}	\overline{OE} LOW to data valid	–	7	–	8	ns
t_{LZOE}	\overline{OE} LOW to low Z	0	–	0	–	ns
t_{HZOE}	\overline{OE} HIGH to high Z ^[9, 10]	–	7	–	8	ns
t_{LZCE}	\overline{CE} LOW to low Z ^[10]	3	–	3	–	ns
t_{HZCE}	\overline{CE} HIGH to high Z ^[9, 10]	–	7	–	8	ns
t_{PU}	\overline{CE} LOW to power-up	0	–	0	–	ns
t_{PD}	\overline{CE} HIGH to power-down	–	15	–	20	ns
t_{DBE}	Byte enable to data valid	–	7	–	8	ns
t_{LZBE}	Byte enable to low Z	0	–	0	–	ns
t_{HZBE}	Byte disable to high Z	–	7	–	8	ns
Write Cycle ^[11, 12]						
t_{WC}	Write cycle time	15	–	20	–	ns
t_{SCE}	\overline{CE} LOW to write end	12	–	13	–	ns
t_{AW}	Address setup to write end	12	–	13	–	ns
t_{HA}	Address hold from write end	0	–	0	–	ns
t_{SA}	Address setup to write start	0	–	0	–	ns
t_{PWE}	\overline{WE} pulse width	12	–	13	–	ns
t_{SD}	Data setup to write end	8	–	9	–	ns
t_{HD}	Data hold from write end	0	–	0	–	ns
t_{LZWE}	\overline{WE} HIGH to low Z ^[13]	3	–	3	–	ns
t_{HZWE}	\overline{WE} LOW to high Z ^[13, 14]	–	7	–	8	ns
t_{BW}	Byte enable to end of write	12	–	13	–	ns

Notes

7. Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3.0 V, and output loading of the specified I_{OL}/I_{OH} and 30-pF load capacitance.
8. This part has a voltage regulator which steps down the voltage from 5 V to 3.3 V internally. t_{power} time has to be provided initially before a read/write operation is started.
9. t_{HZOE} , t_{HZCE} , and t_{HZWE} are specified with a load capacitance of 5 pF as in part (b) of [Figure 2 on page 5](#). Transition is measured ± 500 mV from steady-state voltage.
10. At any given temperature and voltage condition, t_{HZCE} is less than t_{LZCE} , t_{HZOE} is less than t_{LZOE} , and t_{HZWE} is less than t_{LZWE} for any given device.
11. The internal write time of the memory is defined by the overlap of \overline{CE} LOW, and \overline{WE} LOW. \overline{CE} and \overline{WE} must be LOW to initiate a write, and the transition of either of these signals can terminate the write. The input data set-up and hold timing should be referenced to the leading edge of the signal that terminates the write.
12. The minimum write cycle time for Write Cycle No. 3 (\overline{WE} Controlled, \overline{OE} LOW) is the sum of t_{HZWE} and t_{SD} .
13. At any given temperature and voltage condition, t_{HZCE} is less than t_{LZCE} , t_{HZOE} is less than t_{LZOE} , and t_{HZWE} is less than t_{LZWE} for any given device.
14. t_{HZOE} , t_{HZCE} , and t_{HZWE} are specified with a load capacitance of 5 pF as in part (b) of [Figure 2 on page 5](#). Transition is measured ± 500 mV from steady-state voltage.

Switching Waveforms

Figure 4. Read Cycle No. 1 [15, 16]

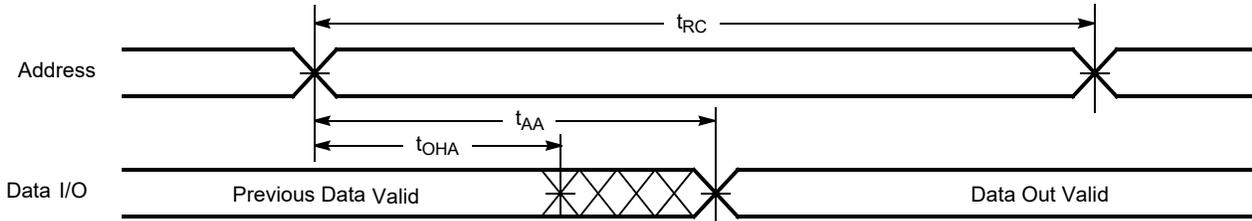
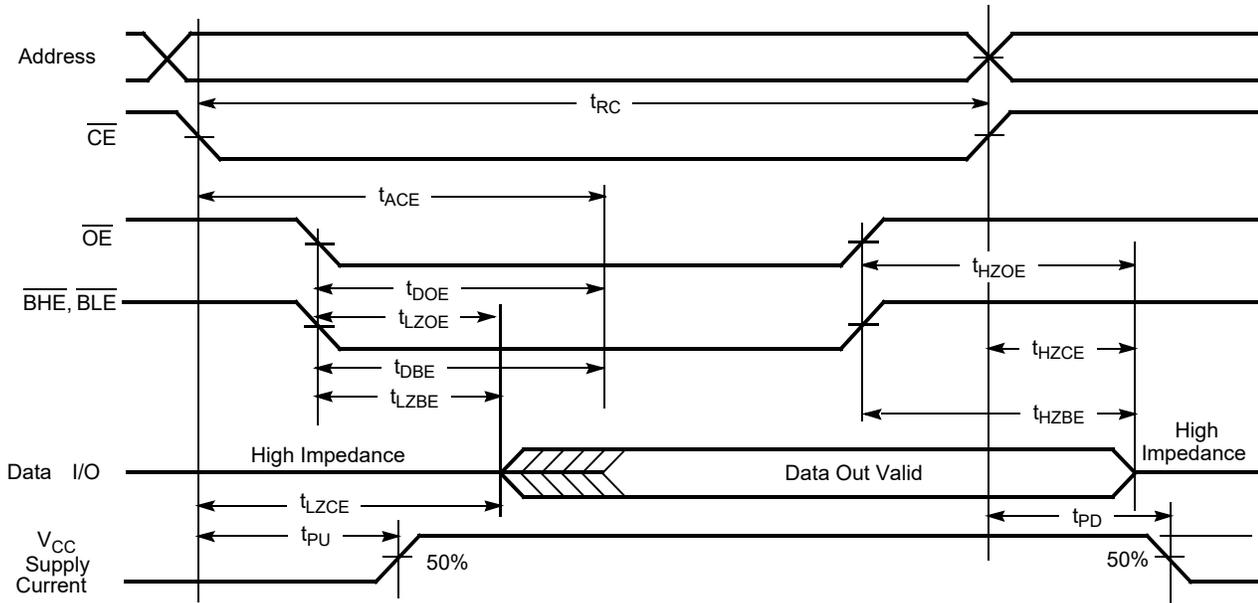


Figure 5. Read Cycle No. 2 (\overline{OE} Controlled) [16, 17]



Notes

- 15. Device is continuously selected. \overline{OE} , \overline{CE} , \overline{BHE} , and/or \overline{BLE} = V_{IL} .
- 16. \overline{WE} is HIGH for read cycle.
- 17. Address valid prior to or coincident with \overline{CE} transition LOW.

Switching Waveforms (continued)

Figure 6. Write Cycle No. 1 (\overline{CE} Controlled) [18, 19]

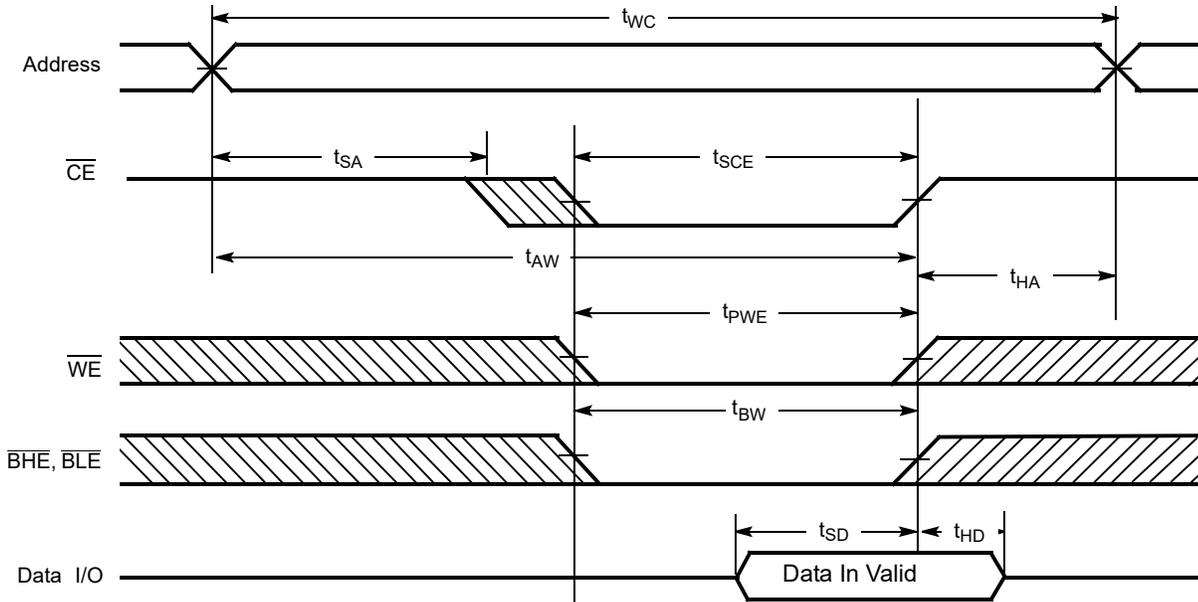
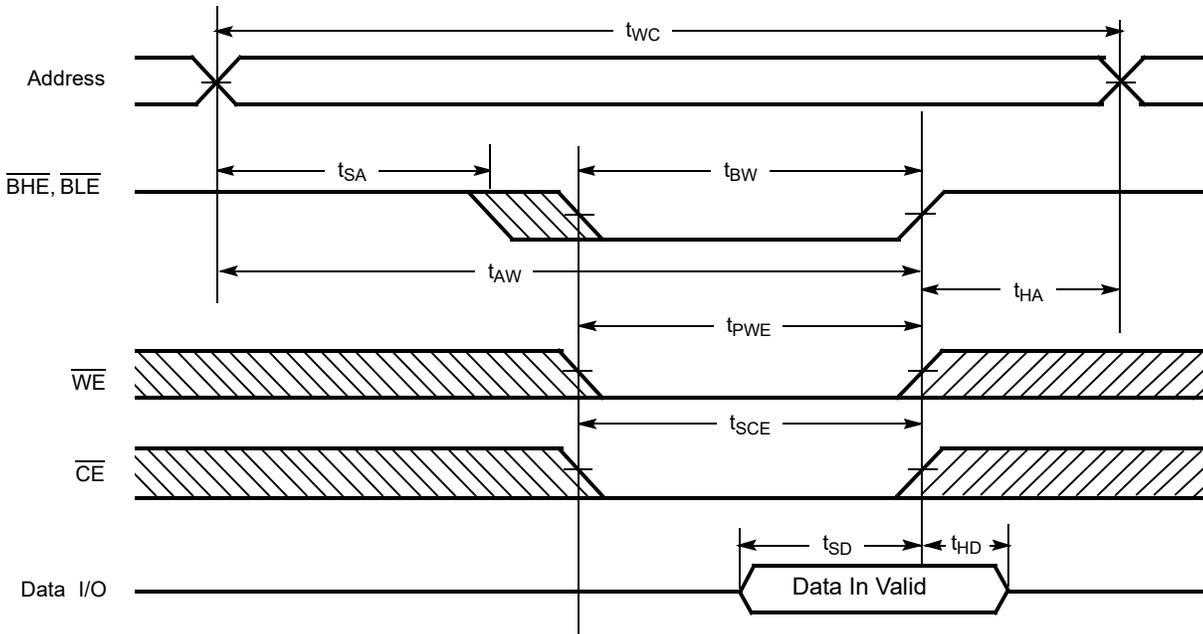


Figure 7. Write Cycle No. 2 (\overline{BLE} or \overline{BHE} Controlled)

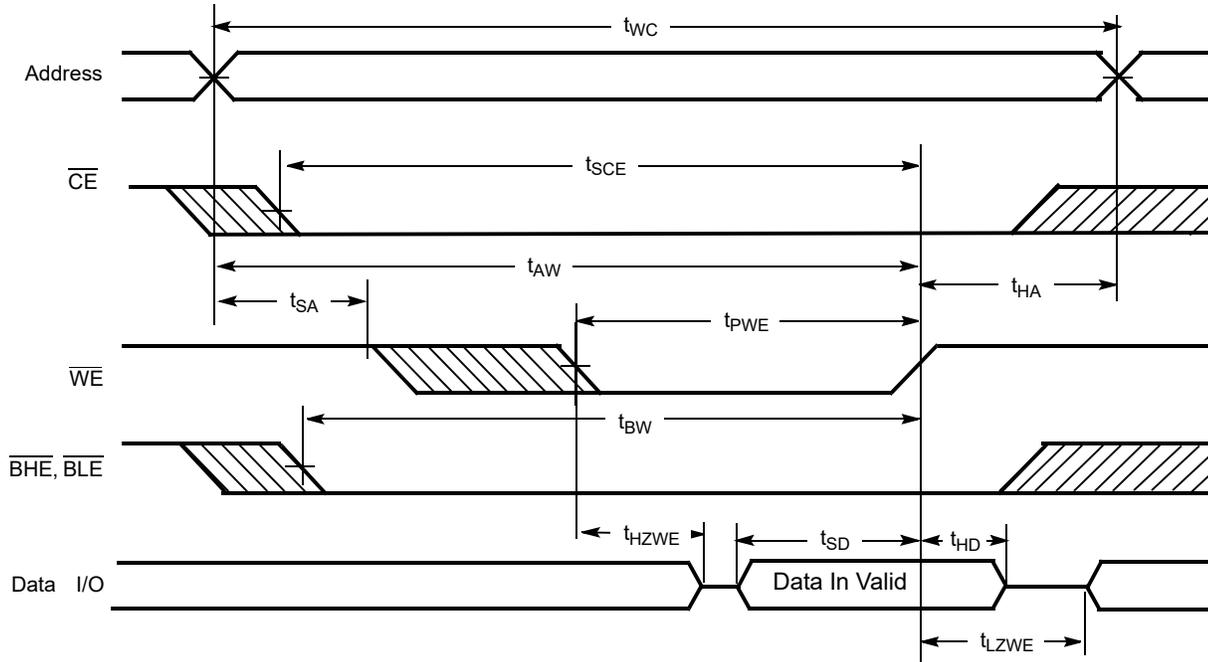


Notes

- 18. Data I/O is high impedance if \overline{OE} or \overline{BHE} and/or $\overline{BLE} = V_{IH}$.
- 19. If \overline{CE} goes HIGH simultaneously with \overline{WE} going HIGH, the output remains in a high-impedance state.

Switching Waveforms (continued)

Figure 8. Write Cycle No. 3 (\overline{WE} Controlled, \overline{OE} LOW) [20]



Note

20. The minimum write cycle pulse width should be equal to the sum of t_{SD} and t_{HZWE} .

Truth Table

$\overline{\text{CE}}$	$\overline{\text{OE}}$	$\overline{\text{WE}}$	$\overline{\text{BLE}}$	$\overline{\text{BHE}}$	I/O ₀ –I/O ₇	I/O ₈ –I/O ₁₅	Mode	Power
H	X	X	X	X	High Z	High Z	Power-down	Standby (I _{SB})
L	L	H	L	L	Data out	Data out	Read all bits	Active (I _{CC})
L	L	H	L	H	Data out	High Z	Read lower bits only	Active (I _{CC})
L	L	H	H	L	High Z	Data out	Read upper bits only	Active (I _{CC})
L	X	L	L	L	Data in	Data in	Write all bits	Active (I _{CC})
L	X	L	L	H	Data in	High Z	Write lower bits only	Active (I _{CC})
L	X	L	H	L	High Z	Data in	Write upper bits only	Active (I _{CC})
L	H	H	X	X	High Z	High Z	Selected, Outputs disabled	Active (I _{CC})
L	X	X	H	H	High Z	High Z	Selected, Outputs disabled	Active (I _{CC})

Ordering Information

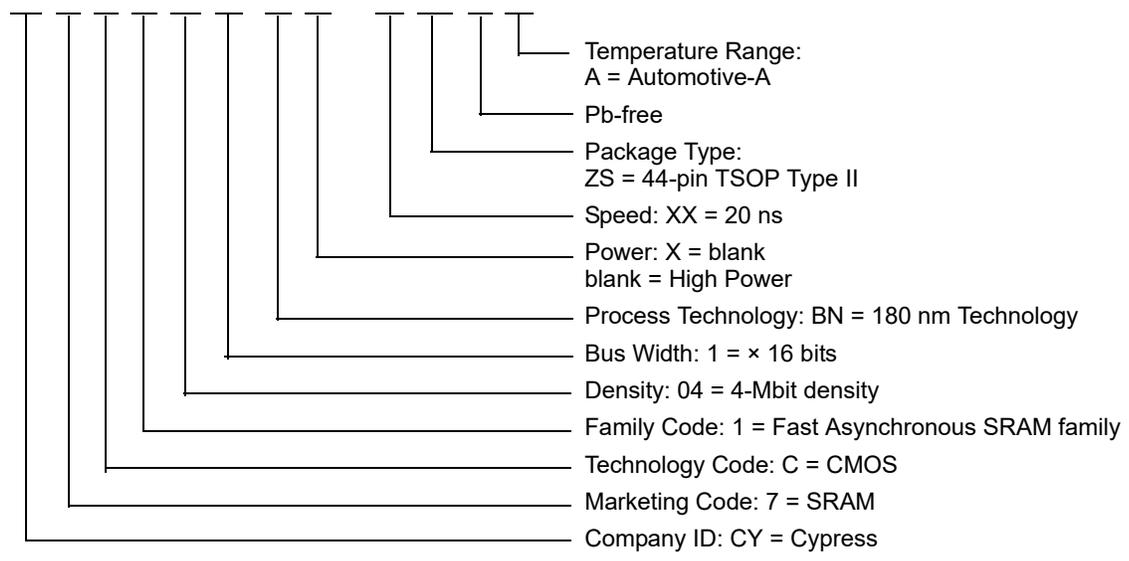
Cypress offers other versions of this type of product in many different configurations and features. The following table contains only the list of parts that are currently available. For a complete listing of all options, visit the Cypress website at <http://www.cypress.com> and refer to the product summary page at <http://www.cypress.com/products> or contact your local sales representative.

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Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
20	CY7C1041BN-20ZSXA	51-85087	44-pin TSOP Type II	Automotive-A

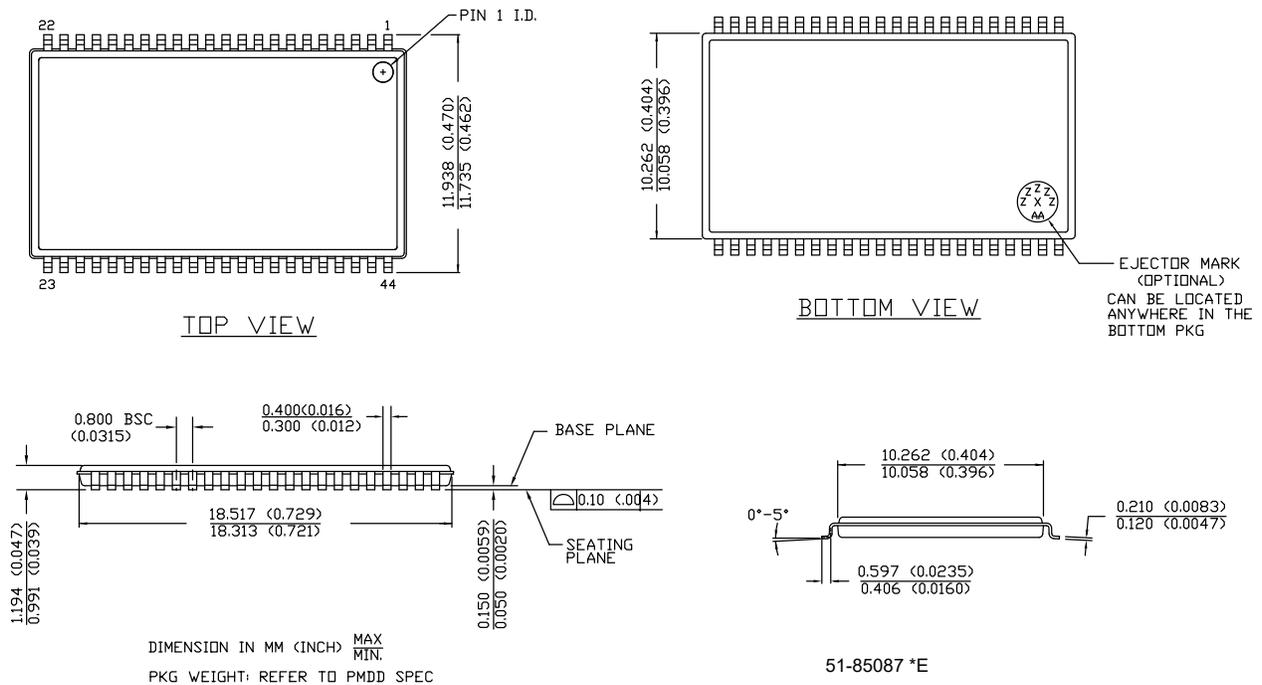
Ordering Code Definitions

CY 7 C 1 04 1 BN X - XX XX X X



Package Diagram

Figure 9. 44-pin TSOP II Package Outline, 51-85087



Acronyms

Acronym	Description
$\overline{\text{BHE}}$	Byte High Enable
$\overline{\text{BLE}}$	Byte Low Enable
$\overline{\text{CE}}$	Chip Enable
CMOS	Complementary Metal Oxide Semiconductor
I/O	Input/Output
$\overline{\text{OE}}$	Output Enable
SRAM	Static Random Access Memory
TSOP	Thin Small Outline Package
$\overline{\text{WE}}$	Write Enable

Document Conventions

Units of Measure

Symbol	Unit of Measure
$^{\circ}\text{C}$	degree Celsius
MHz	megahertz
μA	microampere
mA	milliampere
mV	millivolt
mW	milliwatt
ns	nanosecond
pF	picofarad
V	volt
W	watt

Document History Page

Document Title: CY7C1041BN, 256K × 16 Static RAM Document Number: 001-06496				
Revision	ECN	Orig. of Change	Submission Date	Description of Change
**	424111	NXR	02/02/2006	New data sheet.
*A	498575	NXR	08/31/2006	Added Automotive-A Temperature Range related information in all instances across the document. Updated Ordering Information : Updated part numbers.
*B	2897061	AJU	03/22/2010	Updated Ordering Information : Updated part numbers. Updated Package Diagram : spec 51-85082 – Changed revision from *B to *C. spec 51-85087 – Changed revision from *A to *C.
*C	2906679	NXR	04/07/2010	Updated Ordering Information : Updated part numbers.
*D	3086674	PRAS	11/15/2010	Updated Ordering Information : Updated part numbers. Added Ordering Code Definitions . Updated Package Diagram : Removed spec 51-85082 *C. Added Acronyms . Updated to new template.
*E	3232637	PRAS	04/20/2011	Updated Electrical Characteristics : Changed unit for I _{IX} and I _{OZ} parameters from mA to µA. Added Units of Measure . Updated to new template.
*F	3383869	TAVA	09/26/2011	Removed Industrial Temperature Range related information in all instances across the document. Replaced “Commercial-L” with “Commercial” in all instances across the document. Rearranged sections for better clarity. Updated Switching Waveforms : Modified the notes in figures under Read cycle and Write cycle sections. Updated Package Diagram : spec 51-85087 – Changed revision from *C to *D. Completing Sunset Review.
*G	4113666	VINI	09/04/2013	Updated Package Diagram : spec 51-85087 – Changed revision from *D to *E. Updated to new template. Completing Sunset Review.
*H	4545523	VINI	10/20/2014	Updated Features : Removed “1540 mW (max.)” under “Low active power”. Updated Truth Table : Added a row in the last (to show what happens when both \overline{BLE} and \overline{BHE} are high). Completing Sunset Review.
*I	4576406	VINI	01/16/2015	Updated Functional Description : Added “For a complete list of related documentation, click here .” at the end. Updated Switching Waveforms : Added Note 20 and referred the same note in Figure 8 .

Document History Page (continued)

Document Title: CY7C1041BN, 256K × 16 Static RAM Document Number: 001-06496				
Revision	ECN	Orig. of Change	Submission Date	Description of Change
*J	5508709	VINI	11/03/2016	Updated Ordering Information : Updated part numbers. Updated to new template. Completing Sunset Review.
*K	5977242	AESATMP8	11/27/2017	Updated Cypress Logo and Copyright.
*L	6544621	VINI	04/15/2019	Updated to new template.

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